

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination OHGA ET AL.	
	09/582,495	Examiner	Art Unit
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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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C	US- -			
D	US- -			
E	US- -			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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